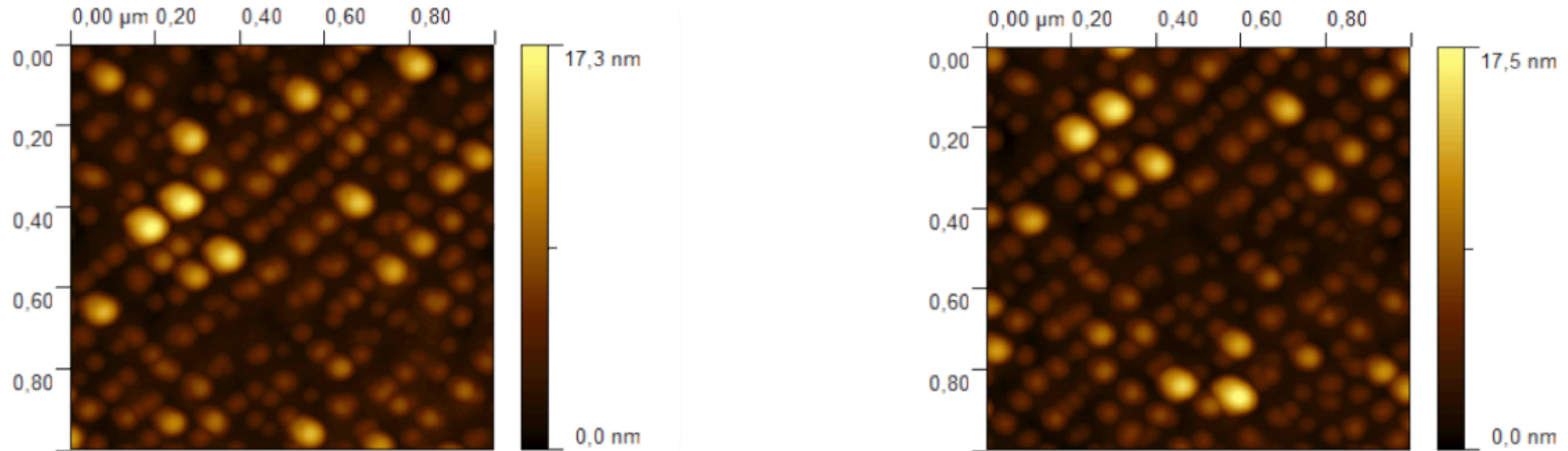
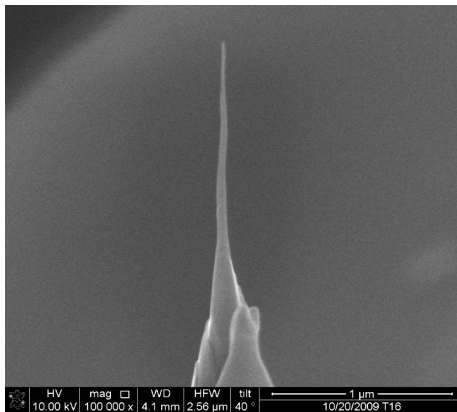


New AFM Probes from CDI show No Wear in over 500 Scans of InAs Quantum Dots



The images above are AFM scans of InAs quantum dots. From left to right, the images represent scans number 28, and 540, all taken sequentially. The images are courtesy of Prof. M. A. Cotta from Unicamp, Brazil, a repeat of their publication in Nano Letters, Vol 8, No. 3 pp 842-847 (2008).



“Even with the extra long length the new CCHAR (Carbon Core High Aspect Ratio) carbon nanotube probes from CDI offer exceptional stability and low noise with good resolution and extra long life when tested on our InAs quantum dot samples”, commented PhD student Alberto Moreau, who carried out the SPM measurements in Brazil.

Moreau used a new probe from CDI featuring over 1m total length produced with a patented, re-reinforced coating to maintain rigidity. The actual probe used is shown at left.

The patented processing technologies used by CDI ensure that the CNT is straight and mounted at precisely the correct angle to ensure that the probe is imaging perpendicular to the surface, thus maintaining the full extreme high-aspect ratio advantage of using CNTs for AFM imaging. CDI can mount CNTs to almost any cantilever. Contact us to discuss your needs.